

IRF530 N-CHANNEL 100V - 0.115 Ω - 14A TO-220 LOW GATE CHARGE STripFET™ II POWER MOSFET

ТҮРЕ	V _{DSS}	R _{DS(on)}	ID
IRF530	100 V	<0.16 Ω	14 A

- TYPICAL $R_{DS}(on) = 0.115\Omega$
- AVALANCHE RUGGED TECHNOLOGY
- 100% AVALANCHE TESTED
- LOW GATE CHARGE
- HIGH CURRENT CAPABILITY
- 175 °C OPERATING TEMPERATURE

DESCRIPTION

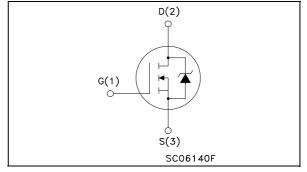
This MOSFET series realized with STMicroelectronics unique STripFET[™] process has specifically been designed to minimize input capacitance and gate charge. It is therefore suitable as primary switch in advanced high-efficiency, high-frequency isolated DC-DC converters for Telecom and Computer applications. It is also intended for any applications with low gate drive requirements.

APPLICATIONS

- HIGH CURRENT, HIGH SWITCHING SPEED
- SOLENOID AND RELAY DRIVERS
- REGULATOR
- DC-DC & DC-AC CONVERTERS
- MOTOR CONTROL, AUDIO AMPLIFIERS
- AUTOMOTIVE ENVIRONMENT (INJECTION, ABS, AIR-BAG, LAMPDRIVERS, etc.)

TO-220	

INTERNAL SCHEMATIC DIAGRAM



Symbol	Parameter	Value	Unit		
V _{DS}	Drain-source Voltage ($V_{GS} = 0$)	100	V		
V _{DGR}	Drain-gate Voltage ($R_{GS} = 20 \text{ k}\Omega$)	100	V		
V _{GS}	Gate- source Voltage	± 20	V		
ID	Drain Current (continuous) at $T_C = 25^{\circ}C$	14	А		
ID	Drain Current (continuous) at $T_C = 100^{\circ}C$	10	A		
I _{DM} (•)	Drain Current (pulsed)	56	A		
P _{tot}	Total Dissipation at $T_C = 25^{\circ}C$	60	W		
	Derating Factor	0.4	W/°C		
dv/dt ⁽¹⁾	Peak Diode Recovery voltage slope	20	V/ns		
E _{AS} ⁽²⁾	Single Pulse Avalanche Energy	70	mJ		
T _{stg}	Storage Temperature	55 to 175	°C		
Тj	Operating Junction Temperature	-55 to 175			
Pulse width	limited by safe operating area.	(1) $I_{SD} \leq 14A$, di/dt $\leq 300A/\mu s$, $V_{DD} \leq V_{(BR)DSS}$, $T_j \leq$	T _{JMAX}		

(1) $I_{SD} \le 14A$, di/dt $\le 300A/\mu$ s, $V_{DD} \le V_{(BR)DSS}$, $T_j \le T_{JMAX}$ (2) Starting $T_j = 25$ °C, $I_D = 14A$, $V_{DD} = 50V$

August 2002

NEW DATASHEET ACCORDING TO PCN DSG/CT/1C02 MARKING: IRF530 @.

ABSOLUTE MAXIMUM RATINGS

IRF530

THERMAL DATA

Rthj-case Rthj-amb T _l	Thermal Resistance Junction-case Thermal Resistance Junction-ambient Maximum Lead Temperature For Soldering Purpose	Max Max	2.5 62.5 300	°C/W °C/W °C
''	Maximum Ecad Temperature For Coldening Fulpose		500	U

ELECTRICAL CHARACTERISTICS (T_{case} = 25 °C unless otherwise specified)

OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0$	100			V
IDSS	Zero Gate Voltage Drain Current (V _{GS} = 0)	V_{DS} = Max Rating V_{DS} = Max Rating T _C = 100°C			1 10	μΑ μΑ
IGSS	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 20 V			±100	nA

ON (*)

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$	I _D = 250 μA	2	3	4	V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} = 10 V	I _D = 7 A		0.115	0.16	Ω

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} ^(*)	Forward Transconductance	V _{DS} = 15 V I _D = 7 A		7		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{DS} = 25V, f = 1 MHz, V _{GS} = 0		458 68 29		pF pF pF

ELECTRICAL CHARACTERISTICS (continued)

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on Delay Time Rise Time			16 25		ns ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V _{DD} = 80V I _D = 14A V _{GS} = 10V		16 3.7 4.7	21	nC nC nC

SWITCHING OFF

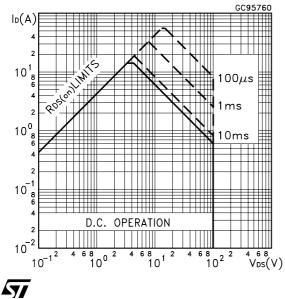
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(off)} t _f	Turn-off Delay Time Fall Time			32 8		ns ns

SOURCE DRAIN DIODE

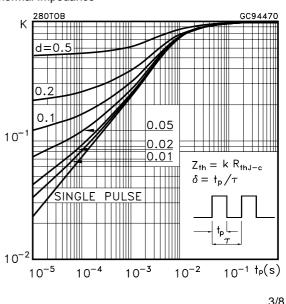
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} (●)	Source-drain Current Source-drain Current (pulsed)				14 56	A A
V _{SD} (*)	Forward On Voltage	$I_{SD} = 14 \text{ A}$ $V_{GS} = 0$			1.6	V
t _{rr} Q _{rr} I _{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$ I_{SD} = 14 A \qquad di/dt = 100 A/\mu s \\ V_{DD} = 10 V \qquad T_j = 150^\circ C \\ (see test circuit, Figure 5) $		92 230 5		ns nC A

(*)Pulsed: Pulse duration = 300 µs, duty cycle 1.5 %.
(•)Pulse width limited by safe operating area.

Safe Operating Area

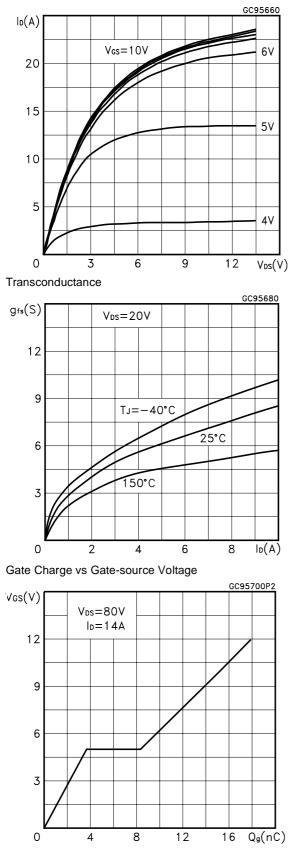


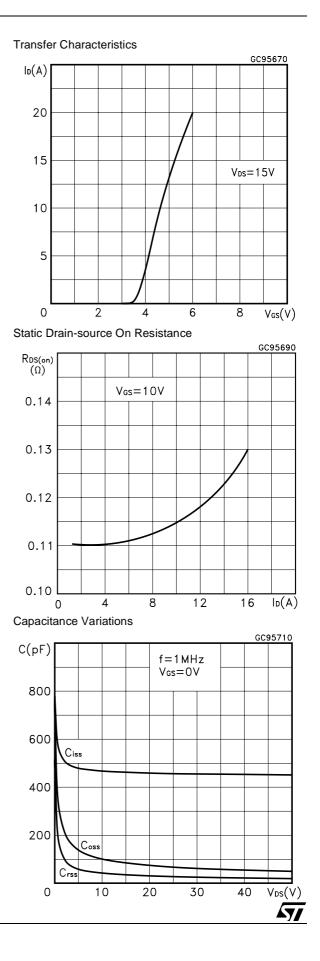
Thermal Impedance

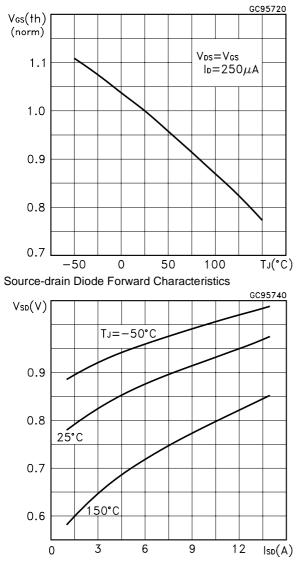


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Output Characteristics

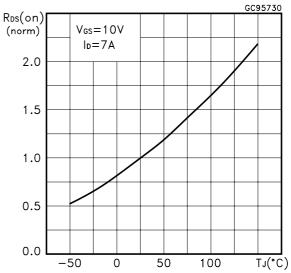




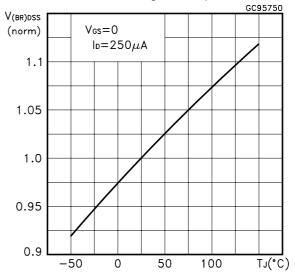


Normalized Gate Threshold Voltage vs Temperature

Normalized on Resistance vs Temperature



Normalized Breakdown Voltage vs Temperature



IRF530

Fig. 1: Unclamped Inductive Load Test Circuit

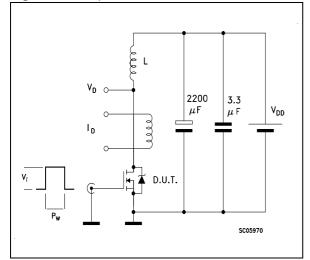
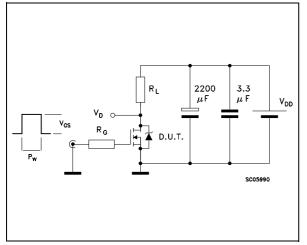
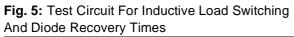


Fig. 3: Switching Times Test Circuits For Resistive Load





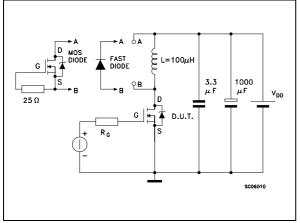


Fig. 2: Unclamped Inductive Waveform

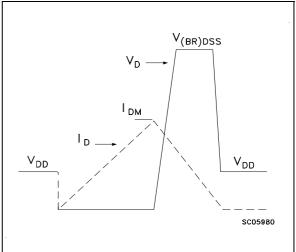
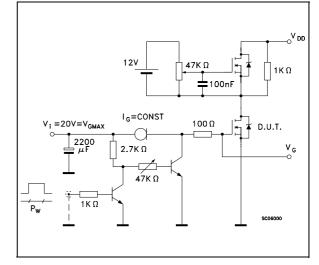
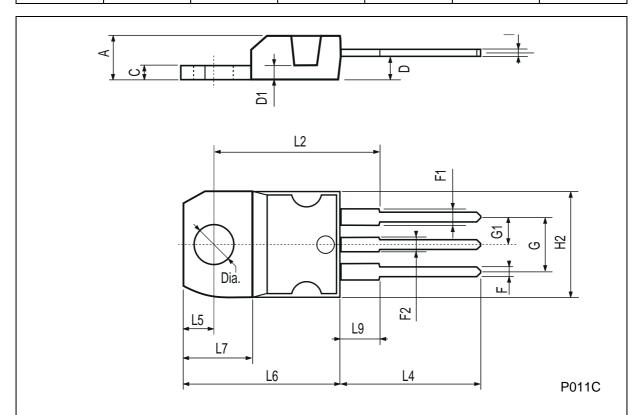


Fig. 4: Gate Charge test Circuit



DIM.		mm				
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	4.40		4.60	0.173		0.181
С	1.23		1.32	0.048		0.051
D	2.40		2.72	0.094		0.107
D1		1.27			0.050	
E	0.49		0.70	0.019		0.027
F	0.61		0.88	0.024		0.034
F1	1.14		1.70	0.044		0.067
F2	1.14		1.70	0.044		0.067
G	4.95		5.15	0.194		0.203
G1	2.4		2.7	0.094		0.106
H2	10.0		10.40	0.393		0.409
L2		16.4			0.645	
L4	13.0		14.0	0.511		0.551
L5	2.65		2.95	0.104		0.116
L6	15.25		15.75	0.600		0.620
L7	6.2		6.6	0.244		0.260
L9	3.5		3.93	0.137		0.154
DIA.	3.75		3.85	0.147		0.151

TO-220 MECHANICAL DATA



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